



# **Features**

- · 200V/1.2A,  $R_{DS(ON)} = 680 \text{m}\Omega(\text{max.}) @ V_{GS} = 10V$
- · ESD Protection
- · 100% UIS + R<sub>q</sub> Tested
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

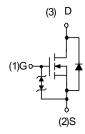
# **Applications**

- DC-DC converter for Networking.
- · Load switch.

# **Pin Configuration**



SOT-23-3



N-Channel MOSFET

# **Absolute Maximum Ratings** (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Rating	Unit		
Common Ratings					
V <sub>DSS</sub>	Drain-Source Voltage	200			
V <sub>GSS</sub>	Gate-Source Voltage	±25	$\neg$ $\lor$		
T <sub>J</sub>	Maximum Junction Temperature	150	- °C		
T <sub>STG</sub>	Storage Temperature Range	-55 to 150			
I <sub>S</sub>	Diode Continuous Forward Current	T <sub>A</sub> =25°C	1.2	А	
	Outline a Build Outline	T <sub>A</sub> =25°C	1.2		
l <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =70°C	0.96	A	
I <sub>DM</sub> <sup>a</sup>	Pulsed Drain Current	T <sub>A</sub> =25°C	4.8	Α	
Б	Maximum Davier Discipation	T <sub>A</sub> =25°C	2.5	10/	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>A</sub> =70°C	1.6	_ W	
R <sub>θJA</sub> <sup>c</sup>	Thermal Resistance-Junction to Ambient	t ≤ 10s	50	°C/W	
		Steady State	90	°C/W	
I <sub>AS</sub> b	Avalanche Current, Single pulse	L=0.5mH	1	А	
E <sub>AS</sub> b	Avalanche Energy, Single pulse	L=0.5mH	0.25	mJ	

Note a: Pulse width limited by max. junction temperature.

Note b : UIS tested and pulse width limited by maximum junction temperature  $150^{\circ}$ C (initial temperature  $T_j=25^{\circ}$ C).

Note c : Surface mounted on 1in<sup>2</sup> pad area.



# **Electrical Characteristics** $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

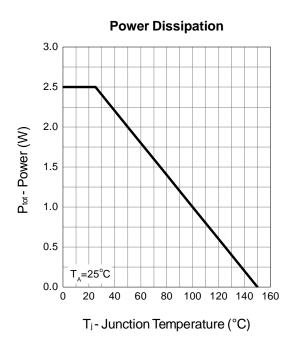
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Static Characteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	200	-	-	V
	Zana Osta Valta as Busin Osmanl	V <sub>DS</sub> =160V, V <sub>GS</sub> =0V	-	-	1	^
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	T <sub>J</sub> =85°C	-	-	30	μΑ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=250\mu A$	3	4	5	V
I <sub>GSS</sub>	Gate Leakage Current	$V_{GS}$ =±25V, $V_{DS}$ =0V	-	-	±10	μΑ
R <sub>DS(ON)</sub> d	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =1A	-	570	680	mΩ
Diode Cha	aracteristics				-	
V <sub>SD</sub> <sup>d</sup>	Diode Forward Voltage	I <sub>SD</sub> =1A, V <sub>GS</sub> =0V	-	0.8	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	1 4A -II /-It 400A/	-	48	-	ns
$Q_{rr}$	Reverse Recovery Charge	$I_{SD}$ =1A, $dI_{SD}/dt$ =100A/ $\mu$ s	-	70	-	nC
Dynamic Characteristics <sup>e</sup>						
$R_{G}$	Gate Resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, $f$ =1MHz	-	4	-	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V,	-	280	-	
C <sub>oss</sub>	Output Capacitance	$V_{DS}=30V$ ,	-	25	-	pF
$C_{rss}$	Reverse Transfer Capacitance	Frequency=1.0MHz	-	8.5	-	
t <sub>d(ON)</sub>	Turn-on Delay Time		-	10	18	
t <sub>r</sub>	Turn-on Rise Time	$V_{DD}=30V, R_L=30\Omega,$	-	8	15	
t <sub>d(OFF)</sub>	Turn-off Delay Time	$-I_{DS}$ =1A, $V_{GEN}$ =10V, $R_{G}$ =6 $\Omega$	-	9	17	ns
t <sub>f</sub>	Turn-off Fall Time		-	2	4	
Gate Charge Characteristics <sup>e</sup>						
Qg	Total Gate Charge		-	6	9	
$Q_{gs}$	Gate-Source Charge	$V_{DS}$ =100V, $V_{GS}$ =10V, $V_{DS}$ =1A		2	-	nC
$Q_{gd}$	Gate-Drain Charge	.00 171	-	1.5	-	

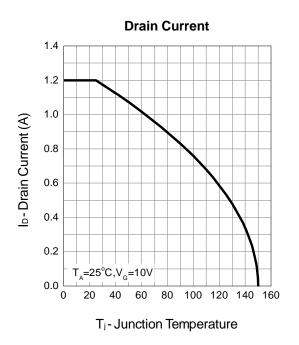
Note d : Pulse test ; pulse width≤300μs, duty cycle≤2%.

Note e: Guaranteed by design, not subject to production testing.

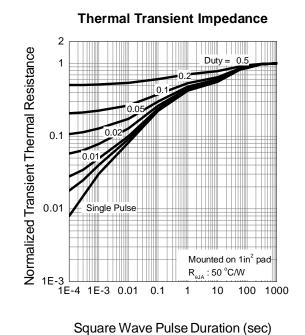


# **Typical Operating Characteristics**



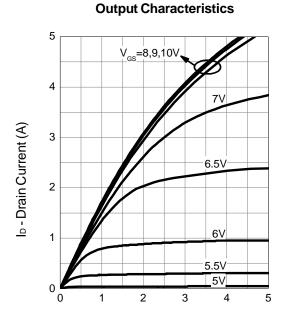


# Safe Operation Area 10 10 10 300µs 1ms 10 10 10 10 10 10 10 Nos - Drain - Source Voltage (V)



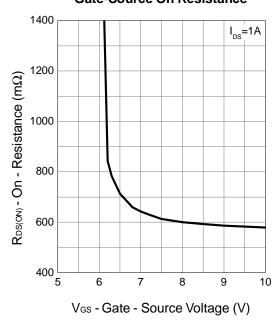


# **Typical Operating Characteristics (Cont.)**

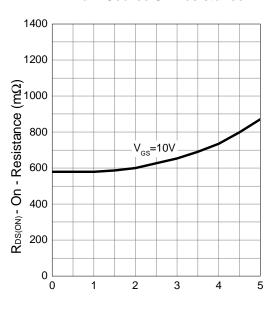


V<sub>DS</sub> - Drain - Source Voltage (V)

# **Gate-Source On Resistance**

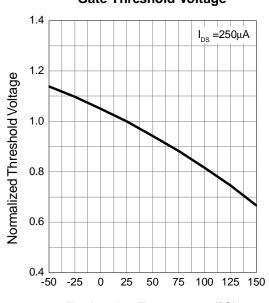


# **Drain-Source On Resistance**



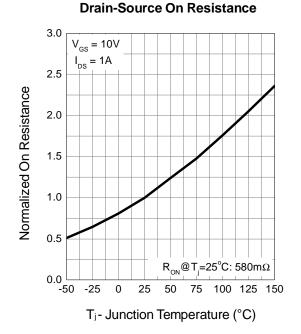
I<sub>D</sub>- Drain Current (A)

# **Gate Threshold Voltage**

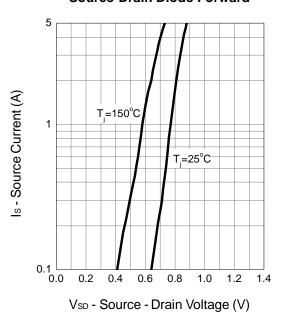




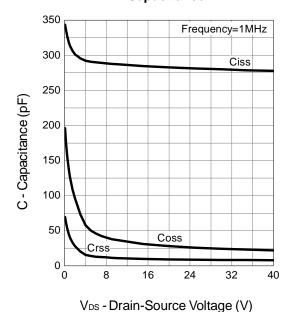
# **Typical Operating Characteristics (Cont.)**



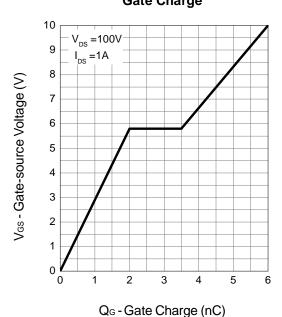
# Source-Drain Diode Forward



# Capacitance



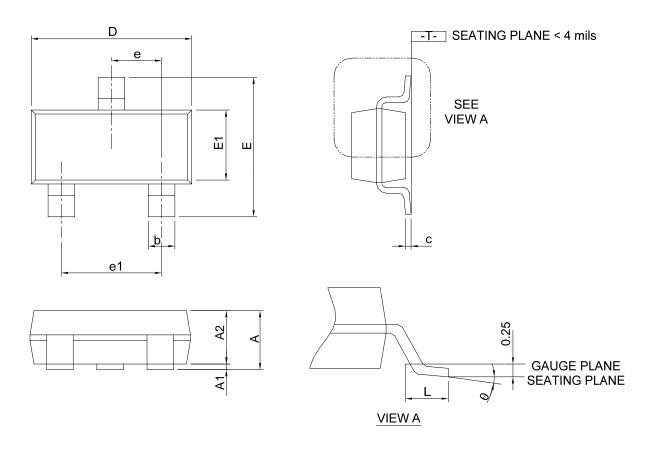
# Gate Charge





**N-Ch MOSFET** 

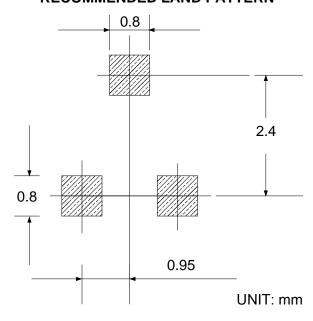
# Package Information SOT-23-3



	SOT-23-3				
SYMBOLS	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	0.90	1.20	0.035	0.047	
A1	0.00	0.08	0.000	0.003	
A2	0.90	1.12	0.035	0.044	
b	0.30	0.50	0.012	0.020	
С	0.08	0.22	0.003	0.009	
D	2.70	3.10	0.106	0.122	
Е	2.60	3.00	0.102	0.118	
E1	1.40	1.80	0.055	0.071	
е	0.95 BSC		0.037	' BSC	
e1	1.9 BSC		0.075 BSC		
L	0.30	0.60	0.012	0.024	
$\theta$	0°	8°	0°	8°	

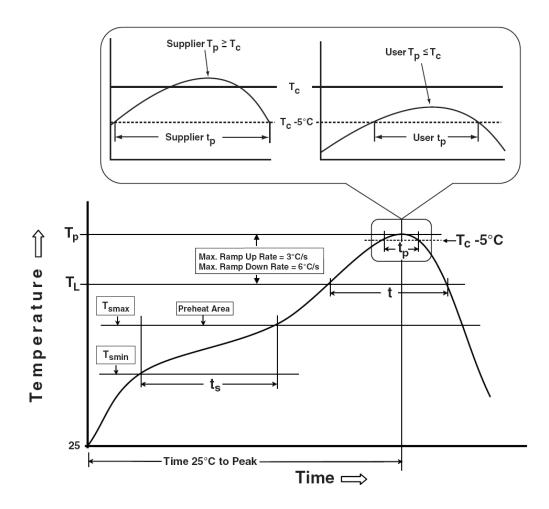
# Note: Dimension D and E1 do not include mold flash, protrusions or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 10 mil per side.

# **RECOMMENDED LAND PATTERN**





# **Classification Profile**





# **Classification Reflow Profiles**

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly	
$\begin{array}{c} \textbf{Preheat \& Soak} \\ \textbf{Temperature min } (\textbf{T}_{smin}) \\ \textbf{Temperature max } (\textbf{T}_{smax}) \\ \textbf{Time } (\textbf{T}_{smin} \text{ to } \textbf{T}_{smax}) \text{ (ts)} \end{array}$	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds	
Average ramp-up rate (T <sub>smax</sub> to T <sub>P</sub> )	3 °C/second max.	3°C/second max.	
Liquidous temperature (T <sub>L</sub> ) Time at liquidous (t <sub>L</sub> )	183 °C 60-150 seconds	217 °C 60-150 seconds	
Peak package body Temperature $(T_p)^*$	See Classification Temp in table 1	See Classification Temp in table 2	
Time $(t_P)^{**}$ within 5°C of the specified classification temperature $(T_c)$	20** seconds	30** seconds	
Average ramp-down rate (T <sub>p</sub> to T <sub>smax</sub> )	6 °C/second max.	6 °C/second max.	
Time 25°C to peak temperature	6 minutes max.	8 minutes max.	
* Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.			

Table 1. SnPb Eutectic Process - Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm³ ³350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> 350-2000	Volume mm <sup>3</sup> >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

# **Reliability Test Program**

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ Tjmax
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ Tjmax
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

<sup>\*\*</sup> Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.



# **Attention**

- 1, Any and all Winsok power products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your Winsok power representative nearest you before using any Winsok power products described or contained herein in such applications.
- 2, Winsok power assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all Winsok power products described or contained herein.
- 3, Specifications of any and all Winsok power products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- 4, Winsok power Semiconductor CO., LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- 5,In the event that any or all Winsok power products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- 6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of Winsok power Semiconductor CO., LTD.
- 7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. Winsok power believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- 8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the Winsok power product that you Intend to use.
- 9, this catalog provides information as of Sep.2014. Specifications and information herein are subject to change without notice.

单击下面可查看定价,库存,交付和生命周期等信息

>>WINSOK(微硕)